

Power MOSFET

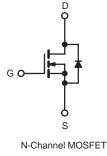
PRODUCT SUMMA	RY	
V _{DS} (V)	650)
R _{DS(on)} (Ω)	$V_{GS} = 10 V$	8.4
Q _g (Max.) (nC)	18	
Q _{gs} (nC)	3.0	
Q _{gd} (nC)	8.9	
Configuration	Sing	le

FEATURES

- Halogen-free According to IEC 61249-2-21 Definition
- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Available in Tape and Reel
- Fast Switching
- Ease of Paralleling
- Compliant to RoHS Directive 2002/95/EC







ABSOLUTE MAXIMUM RATINGS T_{C} =	= 25 °C, unle	ess otherwis	e noted		
PARAMETER			SYMBOL	LIMIT	UNIT
Drain-Source Voltage			V _{DS}	650	V
Gate-Source Voltage		V _{GS}	± 20	v	
Continuous Drain Current	V _{GS} at 10 V	T _C = 25 °C T _C = 100 °C	L_	1.2	
	VGS at 10 V	T _C = 100 °C	= 100 °C I _D 0.8 A		А
Pulsed Drain Current ^a			I _{DM}	4.8	
Linear Derating Factor				0.33	W/°C
Linear Derating Factor (PCB Mount) ^e				0.020	VV/ C
Single Pulse Avalanche Energy ^b			E _{AS}	74	mJ
Repetitive Avalanche Current ^a			I _{AR}	2.0	A
Repetitive Avalanche Energy ^a			E _{AR}	4.2	mJ
Maximum Power Dissipation	$T_C = 2$	25 °C	Р	3	w
Maximum Power Dissipation (PCB Mount) ^e	$T_A = 2$	25 °C	P _D	0.02	vv
Peak Diode Recovery dV/dt ^c			dV/dt	3.0	V/ns
Operating Junction and Storage Temperature Rang	on and Storage Temperature Range T _J , T _{stg} - 55 to + 150		°C		
Soldering Recommendations (Peak Temperature)	for ⁻	10 s		260 ^d	

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. $V_{DD} = 50 \text{ V}$, starting $T_J = 25 \text{ °C}$, L = 37 mH, $R_g = 25 \Omega$, $I_{AS} = 2.0 \text{ A}$ (see fig. 12). c. $I_{SD} \le 2.0 \text{ A}$, dl/dt $\le 40 \text{ A/}\mu\text{s}$, $V_{DD} \le V_{DS}$, $T_J \le 150 \text{ °C}$. d. 1.6 mm from case. e. When mounted on 1" square PCB (FR-4 or G-10 material).

* Pb containing terminations are not RoHS compliant, exemptions may apply



THERMAL RESISTANCE RAT	INGS		_	_	
PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R _{thJA}	-	-	110	
Maximum Junction-to-Ambient (PCB Mount) ^a	R _{thJA}	-	-	50	°C/W
Maximum Junction-to-Case (Drain)	R _{thJC}	-	-	3.0	

Note

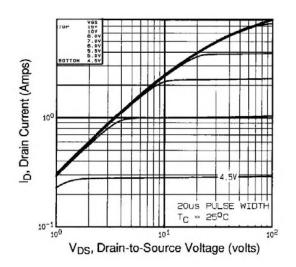
a. When mounted on 1" square PCB (FR-4 or G-10 material).

PARAMETER	SYMBOL	TES	T CONDITIONS	MIN.	TYP.	MAX.	UNIT
Static		·					•
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} =	= 0 V, I _D = 250 μA	650	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference	e to 25 °C, I _D = 1 mA	-	0.88	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	- V _{GS} , I _D = 250 μΑ	2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}	,	V _{GS} = ± 20 V	-	-	± 100	nA
		V _{DS} =	= 600 V, V _{GS} = 0 V	-	-	100	•
Zero Gate Voltage Drain Current	IDSS	V _{DS} = 480 V	′, V _{GS} = 0 V, T _J = 125 °C	-	-	500	μA
Drain-Source On-State Resistance	R _{DS(on)}	$V_{GS} = 10 V$	I _D = 1.2 A ^b	-	8.4	-	Ω
Forward Transconductance	9 _{fs}	V _{DS} :	= 50 V, I _D = 1.2 A	1.4	-	-	S
Dynamic					•	•	
Input Capacitance	C _{iss}		$V_{GS} = 0 V$,	-	350	-	pF
Output Capacitance	Coss		$V_{\rm DS} = -25 \rm V,$	-	48	-	
Reverse Transfer Capacitance	C _{rss}	f = 1.0 MHz, see fig. 5		-	8.6	-	1
Total Gate Charge	Qg			-	-	18	
Gate-Source Charge	Q _{gs}	$V_{GS} = 10 V$	$I_D = 2.0 \text{ A}, V_{DS} = 360 \text{ V},$ see fig. 6 and 13^{b}	-	-	3.0	nC
Gate-Drain Charge	Q _{gd}	1	see ng. o and ro	-	-	8.9	
Turn-On Delay Time	t _{d(on)}			-	10	-	
Rise Time	t _r	- V _{DD} =	300 V, I _D = 2.0 A,	-	23	-	
Turn-Off Delay Time	t _{d(off)}	$R_g = 18 \Omega$,	$R_D = 135 \Omega$, see fig. 10^{b}	-	30	-	ns
Fall Time	t _f	1		-	25	-	
Internal Drain Inductance	L _D	6 mm (0.25") f	Between lead, 6 mm (0.25") from package and center of die contact		4.5	-	nH
Internal Source Inductance	Ls				7.5	-	דיווי ן
Drain-Source Body Diode Characteristic	S						
Continuous Source-Drain Diode Current	I _S	showing the	MOSFET symbol showing the		-	2.0	Α
Pulsed Diode Forward Current ^a	I _{SM}	integral revers p - n junction		-	-	8.0	
Body Diode Voltage	V_{SD}	T _J = 25 °C	, $I_{\rm S}$ = 2.0 A, $V_{\rm GS}$ = 0 V ^b	-	-	1.6	V
Body Diode Reverse Recovery Time	t _{rr}	T 05 °C I	-200 dl/dt -100 A/mb	-	290	580	ns
Body Diode Reverse Recovery Charge	Q _{rr}	$T_J = 25 \text{ °C}, I_F = 2.0 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}^{b}$		-	0.67	1.3	μC
Forward Turn-On Time	t _{on}	Intrinsic tu	-on is dor	ninated b	y L _S and	L _D)	

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Pulse width \leq 300 µs; duty cycle \leq 2 %.





TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



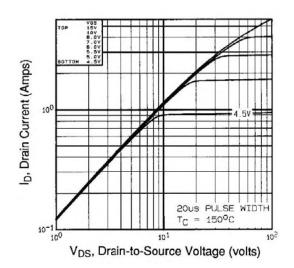


Fig. 2 - Typical Output Characteristics, $T_C = 150 \ ^{\circ}C$

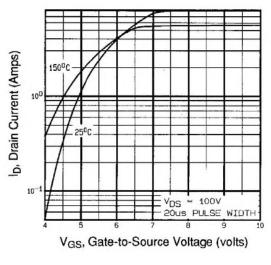


Fig. 3 - Typical Transfer Characteristics

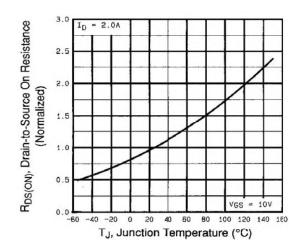


Fig. 4 - Normalized On-Resistance vs. Temperature



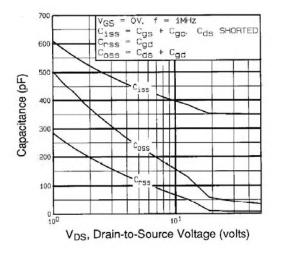
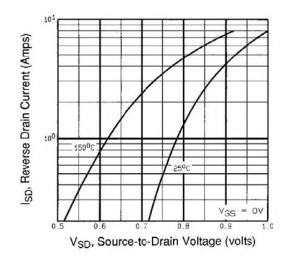


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage





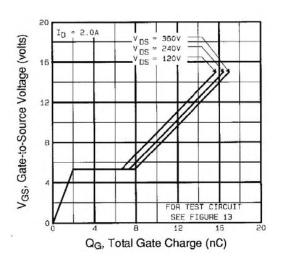


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

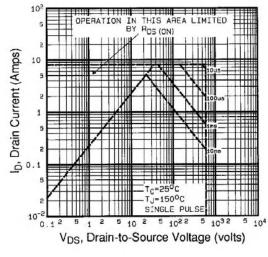


Fig. 8 - Maximum Safe Operating Area



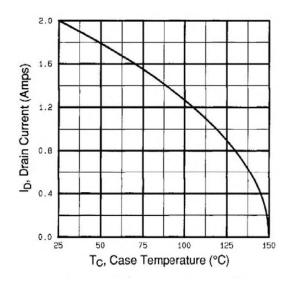


Fig. 9 - Maximum Drain Current vs. Case Temperature

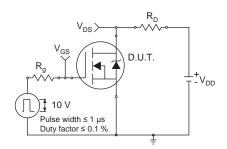


Fig. 10a - Switching Time Test Circuit

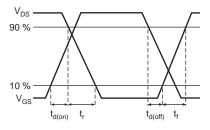
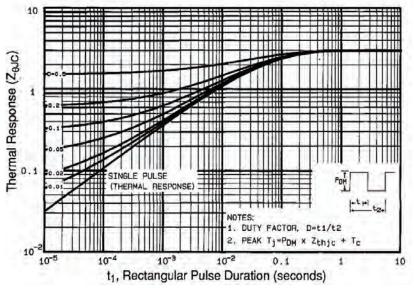


Fig. 10b - Switching Time Waveforms







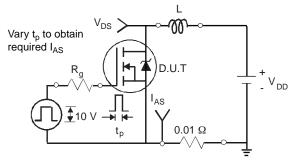


Fig. 12a - Unclamped Inductive Test Circuit

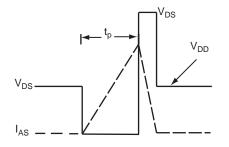


Fig. 12b - Unclamped Inductive Waveforms

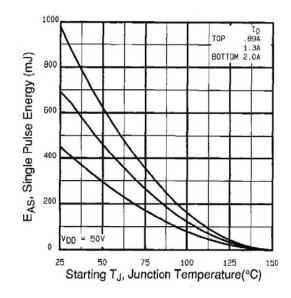


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

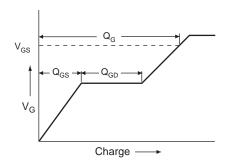


Fig. 13a - Basic Gate Charge Waveform

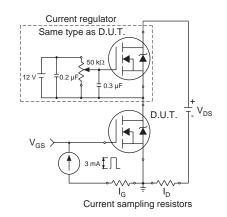
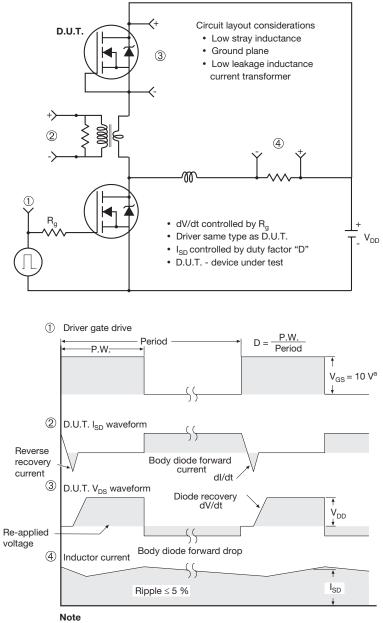


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit

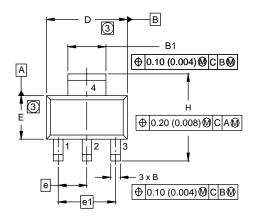


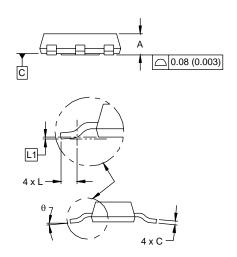
a. V_{GS} = 5 V for logic level devices

Fig. 14 - For N-Channel



SOT-223 (HIGH VOLTAGE)





DIM.	MILLIMETERS		INCHES		
	MIN.	MAX.	MIN.	MAX.	
А	1.55	1.80	0.061	0.071	
В	0.65	0.85	0.026	0.033	
B1	2.95	3.15	0.116	0.124	
С	0.25	0.35	0.010	0.014	
D	6.30	6.70	0.248	0.264	
E	3.30	3.70	0.130	0.146	
е	2.30 BSC		0.0905 BSC		
e1	4.60	BSC	0.181 BSC		
Н	6.71	7.29	0.264	0.287	
L	0.91	-	0.036	-	
L1	0.061 BSC		0.002	4 BSC	
θ	-	10'	-	10'	

Notes

1. Dimensioning and tolerancing per ASME Y14.5M-1994.

2. Dimensions are shown in millimeters (inches).

Dimension do not include mold flash.
Outline conforms to JEDEC outline TO-261AA.



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